



## DATA SHEET



# EMX-1434

"SMART" PXI EXPRESS 4-CHANNEL 204.8 KSA/S  
ARBITRARY WAVEFORM GENERATOR

## APPLICATIONS

Modal / GVT (Ground Vehicle Testing)  
Acoustics  
Shock / Vibration  
Rotational Machinery  
Electronic Test

## FEATURES

### Analog Performance

- 4-channel, 204.8 k Sa/s sample rate per channel
- Dual integrated tach input channels
- Synchronized DSA source
- Rotational measurement capability
- 4 channel DIO
- Advanced system-on-a-chip filtering and analysis
- Precision multi-channel synchronization
- End-to-end internal source self-calibration

### System Level Functionality

- Corporate Wide Cloud Data Management / Access
- Comprehensive Runtime Health Monitoring
- Run-time Self-calibration / Embedded NIST Calibration
- Precision Distributed Measurement Synchronization
- Data Streaming at Full Acquisition Rates on all Channels across PXI Express backplane

### Software

- X-Modal III
- EXLab
- SO Analyzer
- Open Source Drivers



[www.vtiinstruments.com](http://www.vtiinstruments.com)

Specifications contained within this document are subject to change without notice

# OVERVIEW

## High Performance Architecture

The EMX-1434 is an arbitrary source/tach high performance modular PXIe board which has four channels arbitrary sources and two channels tachometer inputs. It is uniquely designed for sound/vibration and DSA applications and can be easily synchronized with digitized data giving the capability to combine the required source and signal analysis into one single chassis to maximize flexibility. It supports various output modes such as Sine, Burst Sine, Chirp, Burst-random and continuous random. It also provides two 64-bit tachometer/counter input channels each of which has a 16k-word FIFO. The module functions as a high-performance arbitrary waveform generator that is also ideal for electronic test applications requiring standard function generator capability, or the need to generate custom-defined waveforms.

With its capability of providing stimulus to a shaker, loudspeaker and other electrical devices, it can be paired with the EMX-4250, EMX-4350, EMX-4380 and EMX-6010 products forming the basis for a versatile dynamic signal analysis system. With the most advanced PXIe and LXI architecture, it can stream numerous waveforms from the host computer to the module, with that ability to synchronize multiple channels in a distributed architecture through the use of IEEE-1588 precision time protocol.

Analog Performance

## Analog Performance

### Built-in Sine and Noise Waveforms

Sine waveform is one of the most common test waveforms. The EMX-1434 provides four independent channels of sine wave capability, each with its own frequency, phase, and amplitude. Sine waves can be generated in continuous and burst modes with frequencies from less than 1Hz to 93 kHz.

The EMX-1434's noise capabilities are specifically designed to provide periodic and pseudo random waveforms in either continuous or burst mode. Additionally, the EMX-1434 can band-translate the noise to have a non-zero start frequency. This allows the user to pinpoint the noise stimulus to frequencies of interest, avoiding troublesome resonances or frequencies that might damage the device under test.

### Arbitrary Waveform

The EMX-1434 can generate arbitrary waveforms to provide simulate virtually any stimulus pattern with a bandwidth up to 80 kHz. Arbitrary waveforms can be downloaded from the host computer and then output a repeating loop. Or the host can continuously download new segments of a waveform to be concatenated with previous segments, allowing continuous, glitch-free playback of any length waveform.

### 24-bit Resolution for dynamic range

The EMX-1434 has a 24-bit DAC per channel and a very high -115dB spurious free dynamic range. The 24-bit DAC ensures superior accuracy and allows the EMX-1434 to output high-fidelity waveforms. The -115dB SFDR maximizes the dynamic performance of the EMX-1434 and is useful for applications where there is a need for smooth output levels over a wide amplitude range.

## Analog Performance

### Built-in Tachometer inputs for Rotating Machinery/Order Analysis Tests

The EMX-1434 has integrated dual tachometer inputs with signal conditioning for a wide range of Tach input signals. These inputs allow tight integration of tachometer information from rotating machinery with acquired data from a digitizer card. This provides the information the floating point processor needs to do RPM triggering of order analysis measurements. Data accuracy can be increased by the fact that the measurement data can be re-sampled and synchronized based on the edge of the tachometer. With the build-in tachometer feature, the EMX-1434 works best with the EMX series DSA products, EMX-4250, EMX-4350, EMX-4380 and EMX-6010 in stimulus and response applications such as rotating machinery and order analysis tests.

### Channel independence and pairing

The EMX-1434 four output channels are grouped in pairs. Both channels of a pair must output the same type of waveform - sine, random or arbitrary. But each pair of channels is completely independent from the other pair. For example, one channel pair can output two uncorrelated random noise signals while the other channel pair and produce two independent sine waves.

### Graceful Shutdown/Safety Feature

Since arbitrary sources can drive very expensive devices under test, it is important to provide an orderly shutdown in case of emergency. In addition to programmable ramp-up and ramp-down rates, the arbitrary source has a smooth ramp-down from AC power failure, or in response to its emergency shutdown input. Furthermore, the EMX-1434 supports < 4 ms fast shutdown for failure conditions and < 5 sec slow shutdown which would be typically used for shaker applications.

## Analog Performance

### Built-in self calibration

Measurement accuracy is maximized utilizing a unique approach for run-time self-calibration eliminating the need to disconnect transducers or field connections. Complete end-to-end self-calibration is performed using a precise onboard voltage reference source permitting execution at test time, at current temperature. This approach not only delivers the most accurate measurements possible, but also validates the instrumentation signal path prior to test.

Complete embedded NIST traceable calibration eliminates the need to remove the instrument from service, resulting in maximum test equipment utilization, reduced need for spares, and reduced down time. The embedded web interface provides a fool-proof, easy to use interface to permit complete traceable calibration, in place, without removing the instrument from service.

## System-level Functionality

Industry standard MATLAB® and Simulink® design tools simplify implementation, maximize re-usability, and provide access to hundreds of standard filters and analysis algorithms.

## System-level Functionality

**Corporate wide cloud data management** delivers advanced data access, security and storage services throughout the organization, accessible from web browsers and other applications, on desktop and mobile devices.

- Simplified, next generation user data services
- Corporate wide data access and security
- Dynamically scalable data management services
- Accessible on a wide range of traditional and mobile devices
- Eliminates need for knowledge of the physical location or configuration of the system

**Comprehensive runtime health monitoring (BIST: Built-in Self-test)** provides test system confidence and peace of mind by ensuring that the complete instrumentation measurement path is functional and delivering the most accurate results possible.

- Ensures runtime instrument performance and accuracy
- Performed without disconnecting external transducer cabling
- Delivers exceptional run-time convenience and measurement confidence
- Instrument performance is verified utilizing precision internal voltage references

**Precision distributed measurement** synchronization ensures that all test data is time correlated whether the instrumentation is centrally located in the laboratory or distributed around a test article.

- Enables widely distributed system level performance
- Utilizes embedded IEEE 1588 precision time protocol
- Precise synchronization across multiple instrumentation modules and chassis
- Synchronization achieved over-the-wire (Ethernet), with complete user transparency

## Software

### Software

Open-source SDRL X-Modal III experimental modal analysis software features intuitive task oriented user interfaces, extensive modal parameter estimation algorithms, parallel display capabilities, flexible data management, and unparalleled channel expandability.

- MATLAB®-based open-source programming environment
- Multiple live parameter estimation windows displayed in parallel
- Task oriented, easy-to-use user interface always "one-click" away
- Simplified "cut & paste" data management and unit's unification tool

**EXLab** is an easy to use, turn-key, data acquisition solution featuring intelligent configuration capabilities, automatic device discovery, extensive time and frequency domain data visualization, and post-acquisition display and analysis tools.

- Intuitive setup and control
- Remote client monitor and control
- Advanced filtering, analysis, and modeling
- Waterfall, video, images, scatter, 3D model and SRS diagrams

**Open Source** industry standard, drivers and programming interfaces provide the flexibility and freedom of choice to select the application programming environment best suited for the application and specific development requirements.

- Support for all major programming environments
- Software interoperability, maintainability, and reusability
- Common development environment and interface across all instrumentation types

## General Specifications

### SOURCE

#### OUTPUT MODES

Sine, burst sine, pseudo random noise, and band translation. Arbitrary waveform with loop or continuous output and burst

#### DIGITAL-TO-ANALOG CONVERTER

Independent 24-bit per channel

#### OVERVOLTAGE PROTECTION

±40 V peak

#### DYNAMIC RANGE

115 dB, 0-51.2 k Hz spurious free

#### THD

-98 dB, to 20 kHz

#### CROSS CHANNEL PHASE MATCH

±0.01° per 1 kHz

#### CROSS CHANNEL AMP MATCH

±0.01 dB 10Hz to 20 kHz

#### SAMPLING RATE

204.8 kSa/s

#### FLATNESS

±0.01 dB to 35 kHz

±0.06 dB 35 kHz to 93 kHz

#### PHASE LINEARITY

±0.005° DC to 10kHz

±0.02° 10 kHz to 30 kHz

±0.5° 30 kHz to 93 kHz

#### CROSSTALK

-100 dB to 10 kHz

-95 dB 10 kHz to 93 kHz

#### MAXIMUM AMPLITUDE

±10 V

#### OUTPUT IMPEDANCE

<0.5 Ω

#### MAXIMUM OUTPUT CURRENT

±25 mA

#### MAXIMUM CAPACITIVE LOAD

Aberrations begin at 20nF

Overshoot and ringing but no oscillation at 1µF

#### RESIDUAL DC OFFSET

<±1mV

### AMPLITUDE CONTROL

#### AMPLITUDE RANGE

-20 dB to 0 dB in 1dB steps

#### AMPLITUDE SCALE FACTOR

0 to 1

#### AMPLITUDE RAMP-DOWN TIME

4 ms

### SINE OUTPUT MODE

#### SHUTDOWN

yes

#### SINE FREQUENCY

0.01 Hz to 93 kHz

#### FREQUENCY RESOLUTION

71 µHz

#### AMPLITUDE ACCURACY

±0.05 dB

#### GENERATED FREQUENCY ACCURACY

Clock source dependent; internal clock 50ppm.

### NOISE OUTPUT MODE

#### FREQUENCY SPANS

80 KHz or 51.2 KHz Full Span – with/without Decimated by 5 and/or Decimated by 2 with maximum of 16 times

#### PASSBAND FLATNESS

< 1.2dBpp

#### CREST FACTOR

4:1 (Typical)

#### PERCENT IN-BAND ENERGY

> 90% (Typical)

#### MINIMUM SPAN

Full Span / (5\*2<sup>16</sup>)

#### CENTER FREQUENCY RESOLUTION

71 µHz

FREQUENCY AND BAND TRANSLATION	MIN SPAN	MAX SPAN	MAX CENTER FREQUENCY
FS = 204.8 KHZ	0.244140625 Hz	80 KHz	80 KHz
FS = 131.072 KHZ	0.15625 Hz	51.2 KHz	51.2 KHz

## General Specifications

### ARBITRARY OUTPUT MODE

MAXIMUM SIGNAL BANDWIDTH  
 BUFFER SIZE  
 CONTINUOUS ARB DATA RATE

80 KHz or 51.2KHz  
 64K Samples x 2 Buffers  
 User must supply data @ rate =  $F / (5^m) * (2^n)$   
 Where  $F_s = 204.8\text{KHz}$  or  $131.072\text{KHz}$   
 $m = 0$  or  $1$   
 $n = 0, 1, 2, \dots, 16$

### CONSTANT LEVEL OUTPUT

OUTPUT LEVEL AT 1KHZ  
 RESIDUAL DC OFFSET

$\pm 10\text{V}$  peak  
 $< \pm 1\text{mV}$

### SUMMER INPUT

MAXIMUM INPUT  
 GAIN, SUMMER INPUT TO SIGNAL OUTPUT 1  
 INPUT IMPEDANCE  
 FLATNESS

$\pm 10\text{V}$  peak  
  
 2 k $\Omega$   
 $\pm 0.01$  dB to 35 kHz  
 $\pm 0.06$  dB 35 kHz to 93 kHz

### TACHOMETER

INPUTS  
 FREQUENCY INPUT RANGE  
 RANGES

2  
 1 MHz  
 $\pm 25\text{V}$   
 $\pm 250\text{V}$   
 Differential  
 DC, AC 0.6 Hz  
 600 nS  
 Programmable  $\pm 95\%$  of range  
 Programmable  $\pm 1\%$  of range

INPUT TYPE  
 INPUT COUPLING  
 MINIMUM PULSE WIDTH  
 THRESHOLD  
 HYSTERESIS

### DIGITAL I/O

CHANNELS  
 VIN HIGH  
 VIN LOW  
 VOUT HIGH  
 VOUT LOW  
 OVERVOLTAGE PROTECTION  
 MAX SLEW RATE  
 SHUTDOWN INPUT

4  
 3.5 V min  
 1.5V max  
 $4.9\text{V} - I_{out} * 100\ \Omega$   
 $+0.1\text{V} + I_{out} * 100\ \Omega$   
 $\pm 15\text{V}$  peak  
 50 V/ $\mu\text{s}$   
 A normally open contact between GND (SMB shell) and a  
 38 k $\Omega$  resistor pulled up to +5 V (SMB center).

Note: that this is not a safety rated shutdown and that if a safety rated shutdown is required then the user is responsible for such, not VTI Instruments.



## Mechanical Specifications

### IEEE 1588 CLOCK SPECIFICATIONS

CLOCK OSCILLATOR ACCURACY  
 SYNCHRONIZATION ACCURACY  
 TIMESTAMP ACCURACY  
 RESOLUTION

±50 ppm  
 Reports "synchronized" when < ±100 ns of the 1588 master clock  
 As good as time synchronization down to 50 ns  
 25 ns

### IEEE 1588-BASED TRIGGER TIMING

#### ALARM

TRIGGER TIME ACCURACY  
 TIME TO TRIGGER DELAY

As good as time synchronization down to 50 ns  
 50 ns

#### RECEIVE LAN [0-7] EVENT

TRIGGER TIME ACCURACY  
 TIME TO TRIGGER DELAY

As good as time synchronization down to 50 ns

Future timestamp  
 Past/zero timestamp

50 ns typical  
 1 ms maximum

### HARDWARE TRIGGER TIMING

DIO BUS  
 TIME TO TRIGGER DELAY

57 ns typical

## Environmental Specifications

### TEMPERATURE

OPERATING  
 STORAGE

0 °C to +50 °C  
 -40 °C to +70 °C

### RELATIVE HUMIDITY

5% - 95% (non-condensing)

### ALTITUDE

3000 m

### SHOCK AND VIBRATION

Conforms to MIL-PRF-28800F

#### RANDOM VIBRATION

10 Min per Axis, MIL-PRF-28800F Class 3

#### SINUSOIDAL

5 to 55hz Resonance Search per MIL-PRF-28800F Class 3, each Axis

#### SHOCK

30g/Axis, 11mS half Sine pulse per MIL-PRF-28800F Class 3

### Notes:

- 1) All specifications are typical unless otherwise stated as a minimum or maximum.
- 2) All specifications subject to change without notice.
- 3) All specifications assume within 24 hours and 5°C of self-calibration temperature unless otherwise specified.

## Ordering Information

	PART NUMBER	
EMX-1434	70-0409-008R	4-Channel, 204.8 kSa/s Smart Arbitrary
<b>SOFTWARE</b>		
X-MODAL III		Modal Analysis Software
SO ANALYZER		Acoustics/Impact/Rotational/Shock Software
EXLAB*		General Purpose DAQ Software
*Multiple configurations available		
<b>RELATED PRODUCTS</b>		
EMX-4350	70-0409-002R	4-Channel, 625k Sa/s Smart Dynamic Signal Analyzer
EMX-4250	70-0409-004R	16-Channel, 204.8k Sa/s Smart Dynamic Signal
EMX-4251	70-0409-012R	Analyzer 8-Channel, 204.8k Sa/s DSA Digitizer
EMX-4008	70-0409-010R	8-Channel Break-out box for EMX-4250/4251
EMX-4016	70-0409-015R	16-Channel Break out box for EMX-4250/4251